

APPRAISER : DNN fault resilience analysis employing approximation errors

Taheri, Mahdi; Ahmadilivani, Mohammad Hasan; Jenihhin, Maksim; Daneshtalab, Masoud; Raik, Jaan 2023 26th International Symposium on Design and Diagnostics of Electronic Circuits and Systems (DDECS) 2023 / p. 124–127 : ill <https://ddecs2023.taltech.ee/> <https://doi.org/10.1109/DDECS57882.2023.10139468>

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